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Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. UDL1P065 Applicant: Parvin et al. Filing Date October 10, 2001	Application No. 09/889,186 Group Unassigned 2878
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U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
OG	A	5,750,991	05/12/98	Moyers et al.			
OG	B	5,155,365	10/13/92	Cann et al.			
	C						
	D						
	E						
	F						
	G						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
OG	H	62-91879	04/27/87	Japan				
OG	I	WO 00/42446	01/11/00	PCT				
	J							
	K							
	L							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
OG	M	"Standard Test Method for Nondestructive Assay of Special Nuclear Material in Low-Density Scrap and Waste by Segmented Passive Gamma-Ray Scanning," September 1996, American Society for Testing and Materials.
OG	N	"Standard Test Method for Nondestructive Assay of Special Nuclear Material in Low Density Scrap and Waste by Segmented Passive Gamma-Ray Scanning," November 1989, American Society for Testing and Materials.
OG	O	Parker et al., "Transmission Measurement Correction for Self-Attenuation in Gamma-Ray Assays of Special Nuclear Materials," 1976, Nuclear Materials Management.

Examiner <i>Oliver Gale</i>	Date Considered <i>05/13/03</i>
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Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.